

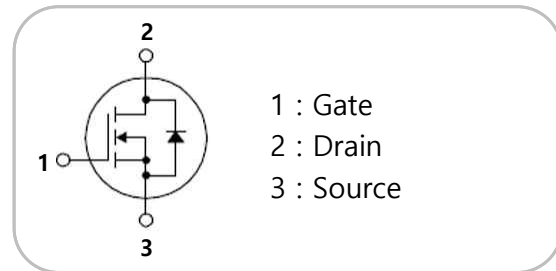
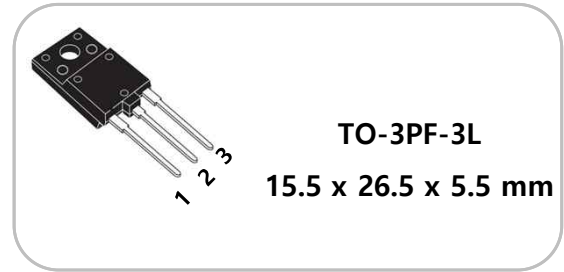
General description

Symbol	Value
V_{DSS} @ $T_C=25^\circ\text{C}$	Min 900V
I_D @ $T_C=25^\circ\text{C}$	9.0A
$R_{DS(on)}$	Max 1.4Ω
Q_G	Typ 52nC

Features

- Gate Charge(Typ. $Q_G=52\text{nC}$)
- High Voltage (Min. $V_{DSS}=900\text{V}$)
- 100% Avalanche Tested

Package



Maximum Ratings ($T_C = 25^\circ\text{C}$)

Parameter	Symbol	Test Condition	Value	Units
Drain-source voltage	V_{DSS}	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	900	V
Drain current (DC)	I_D	$T_C=25^\circ\text{C}$	9.0	A
		$T_C=100^\circ\text{C}$	5.7	A
Drain current (Pulsed)	I_{DM}	Pulse width limited by junction temperature	36	A
Gate-source voltage	V_{GS}	-	±30	V
Single pulsed avalanche energy	E_{AS}	$I_{AS}=9.0\text{A}$, $R_G=25\Omega$, $V_{DD}=50\text{V}$, $L=21\text{mH}$	900	mJ
Power dissipation	P_D	$T_C=25^\circ\text{C}$	130	W
Operating junction	T_j	-	-55 to 150	$^\circ\text{C}$
Storage temperature	T_{stg}	-	-55 to 150	$^\circ\text{C}$




Electrical Characteristics ($T_j = 25^\circ\text{C}$)

Parameter	Symbol	Test Condition				Units
			Min	Typ	Max	
Drain-source breakdown voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\mu A$	900	-	-	V
Zero gate voltage drain current	I_{DSS}	$V_{DS}=900V, V_{GS}=0V$	-	-	1.0	μA
Gate-source leakage current	I_{GSS}	$V_{GS}=\pm 30V, V_{DS}=0V$	-	-	± 100	nA
Gate threshold voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	3.0	-	5.0	V
Drain-source on-state resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=4.5A$	-	1.2	1.4	Ω
Input capacitance	C_{iss}	$V_{DS}=25V, V_{GS}=0V$ $f = 1\text{MHz}$	-	2100	-	pF
Output capacitance	C_{oss}		-	175	-	
Reverse transfer capacitance	C_{rss}		-	14	-	
Total gate charge	Q_G	$V_{DS}=720V, V_{GS}=10V,$ $I_D=9A$	-	52	68	nC
Gate-source charge	Q_{GS}		-	16		
Gate-drain charge	Q_{GD}		-	20	-	
Turn on delay time	$t_{d(on)}$	$V_{DD}=450V, I_D=9A,$ $R_G=25\Omega$	-	50	-	ns
Rise time	t_r		-	120	-	
Turn off delay time	$t_{d(off)}$		-	100	-	
Fall time	t_f		-	75	-	




Body Diode(Source – Drain) Electrical Characteristics (T_j = 25°C)

Parameter	Symbol	Test Condition	Value			Units
			Min	Typ	Max	
Continuous diode forward current	I _S	-	-	-	9.0	A
Maximum pulsed drain to source diode forward current	I _{SM}	-	-	-	36.0	A
Forward voltage	V _{SD}	I _{SD} =9A, V _{GS} =0V	-	-	1.4	V
Reverse recovery time	t _{rr}	I _{SD} =9A, V _{GS} =0V di/dt=100A/μs	-	550.0	-	ns
Reverse recovery charge	Q _{rr}		-	6.5	-	uC

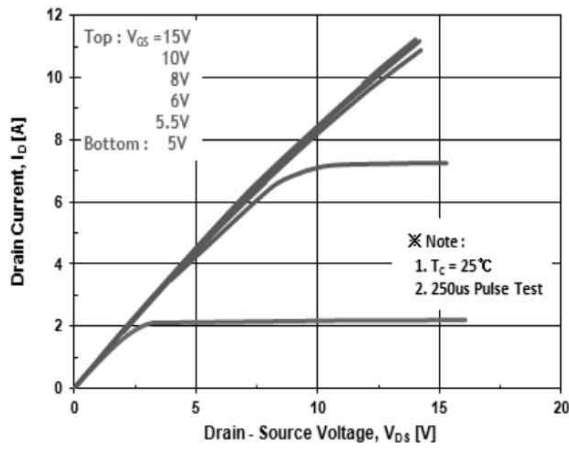

Thermal Characteristics(T_C = 25°C)

Symbol	Parameter	Typ	Max	Units
R _{th(j-c)}	Junction to case	-	0.96	°C/W

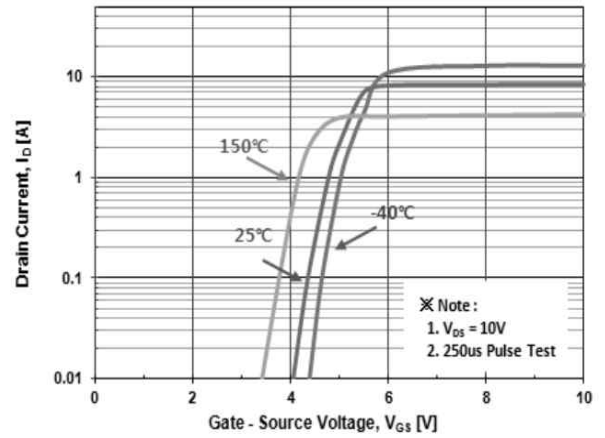


Typical Electrical Characteristics Curves (T_j = 25°C)

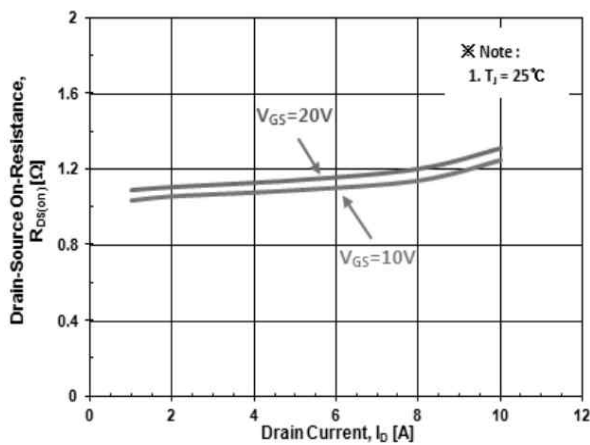
V_{DS} – I_D Characteristics



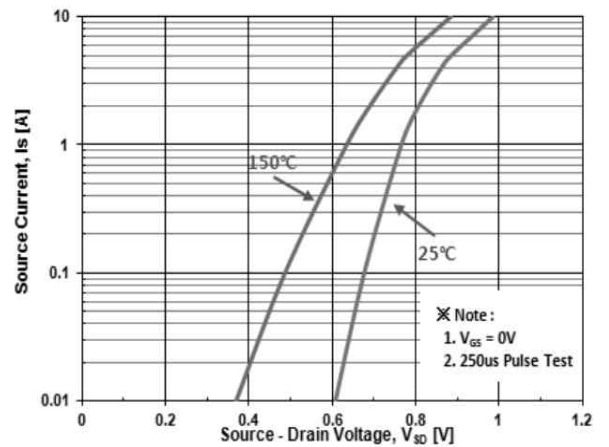
V_{GS} – I_D Characteristics



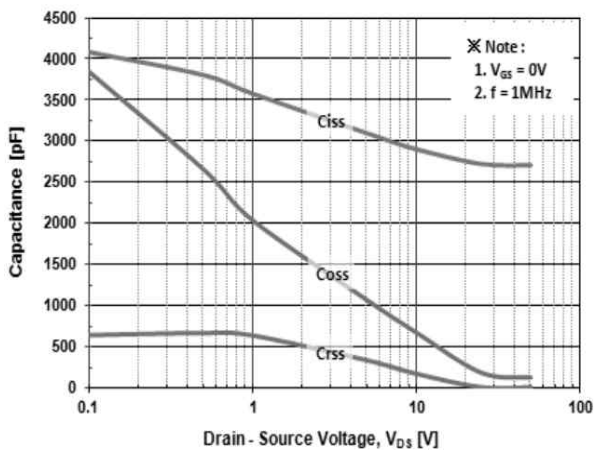
I_D – R_{DS(on)} Characteristics



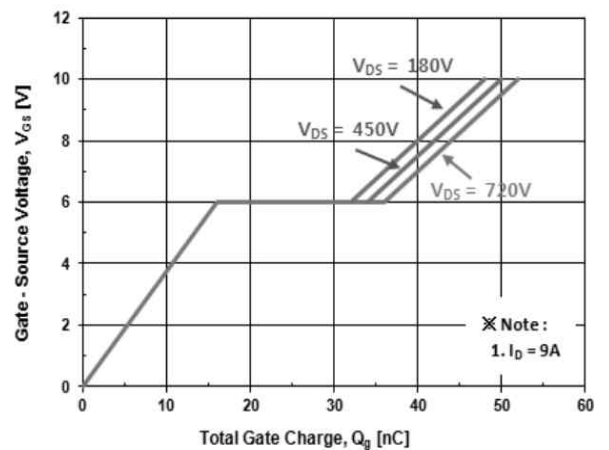
V_{SD} – I_S Characteristics



V_{DS} – C_T Characteristics

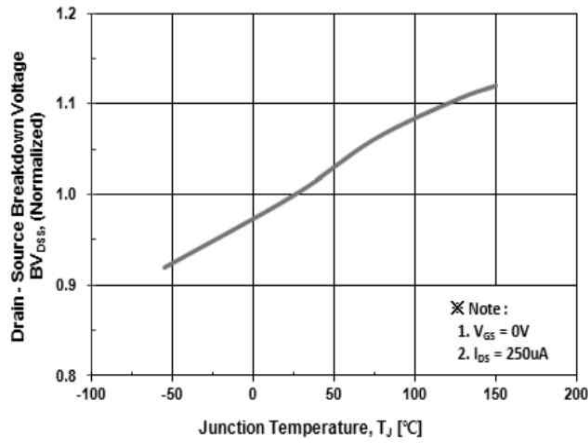


Q_g – V_{GS} Characteristics

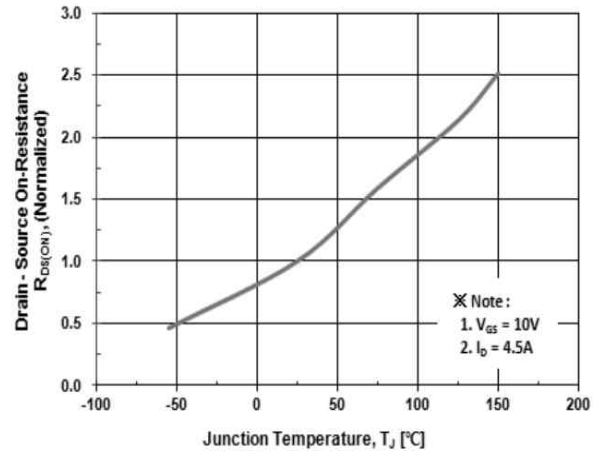


Typical Electrical Characteristics Curves (T_j = 25°C)

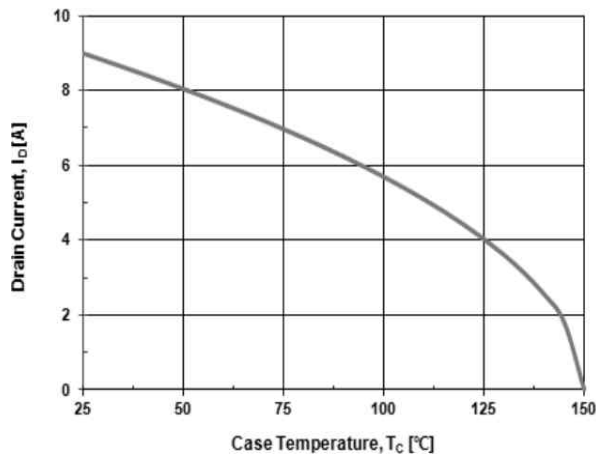
T_j – V_{DSS(Normalized)} Characteristics



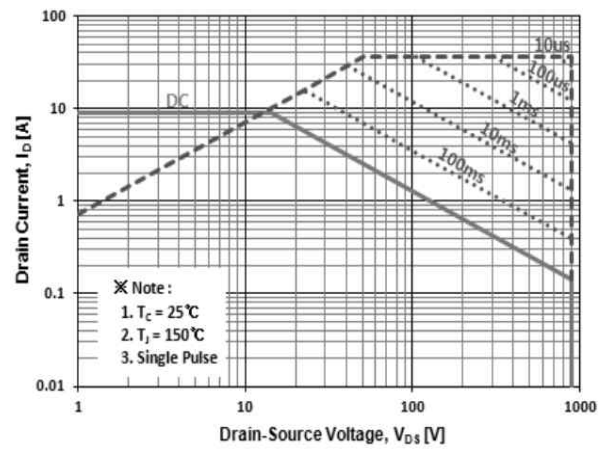
T_j – R_{DS(on)(Normalized)} Characteristics



T_c – I_D Characteristics



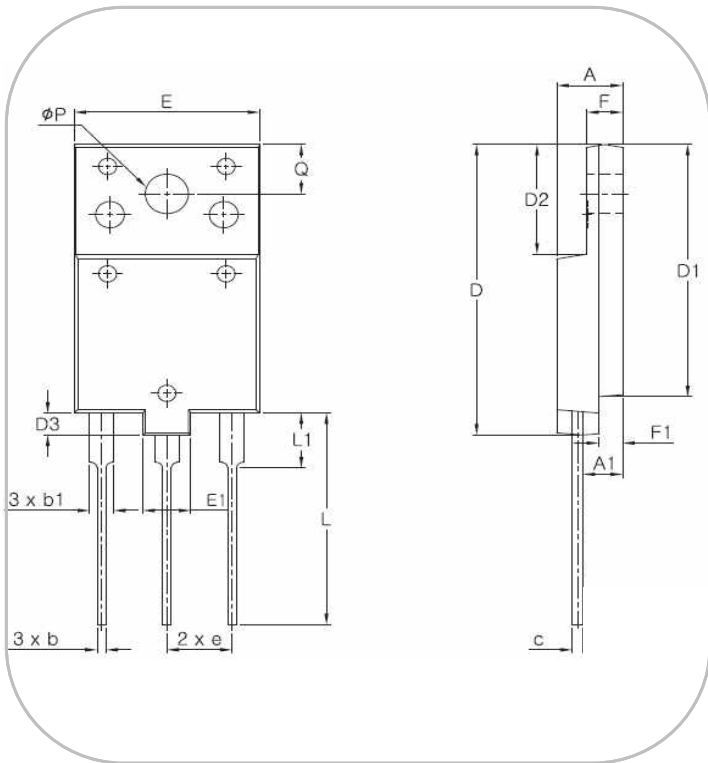
SOA Characteristics



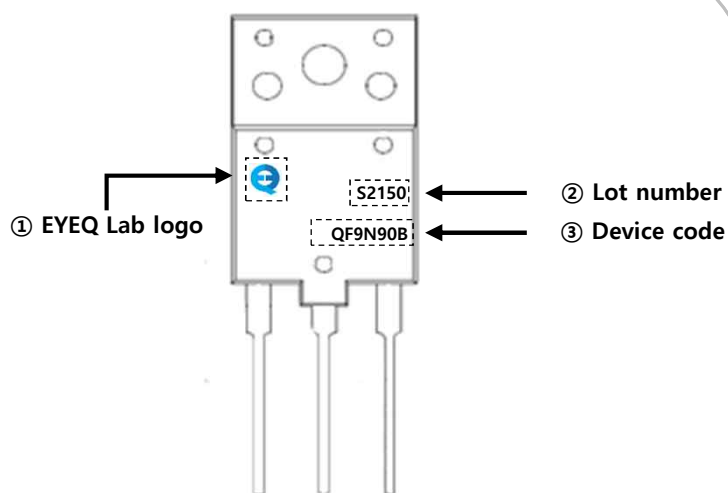
Package Dimensions(TO-3PF-3L)

[Unit : mm]

SYMBOL	MIN	MAX
A	5.30	5.70
A1	3.10	3.50
b	0.65	0.85
b1	1.80	2.20
c	0.80	1.00
D	26.30	26.70
D1	22.80	23.20
D2	9.80	10.20
D3	1.80	2.20
E	15.30	15.70
E1	3.80	4.20
e	5.15	5.75
F	2.80	3.20
F1	1.80	2.20
L	19.10	19.50
L1	4.80	5.20
Q	4.30	4.70
φP	3.40	3.80



Marking Information



- ① Company Logo
- ② Lot Number : 21 – 2021 Year , 50 – 50 Week
- ③ Device Code : Q – EYEQ Lab, F – MOSFET,
9 – 9A, N – NPN Type, 90 – 900V

